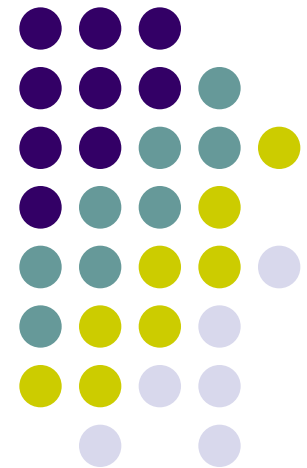
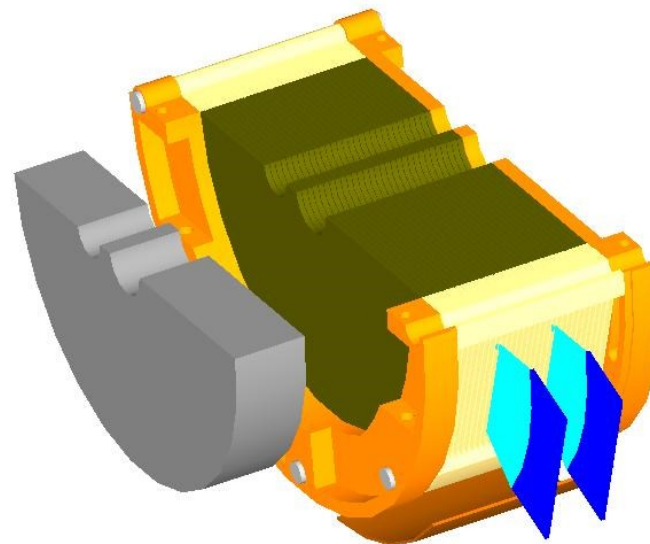




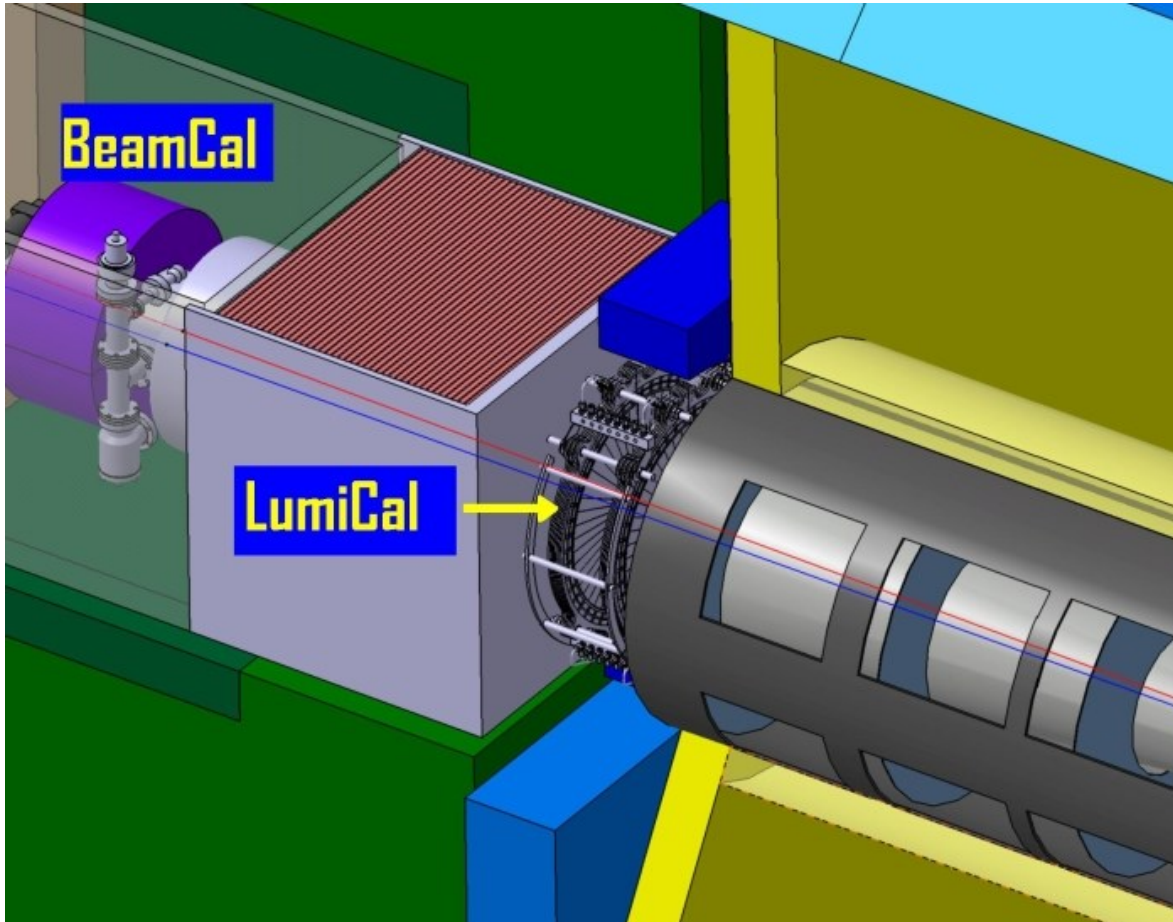
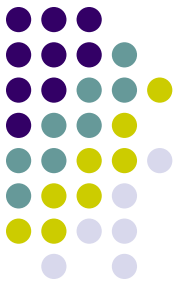
BeamCal sensors overview



Sergej Schuwalow, DESY Hamburg



BeamCal sensor requirements



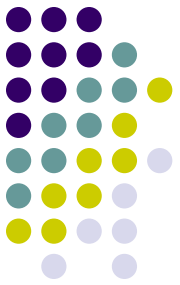
BeamCal should be compact, small Moliere radius needed:
- sampling calorimeter with solid state sensors, tungsten as absorber.

Severe load at small radii due to beamstrahlung:
- radiation hard sensors (up to 1 MGy annual dose)

Bunch-by-bunch operation:
- fast response of sensors

Test beam studies, physical calibration:
- **sensitivity to MIPs**

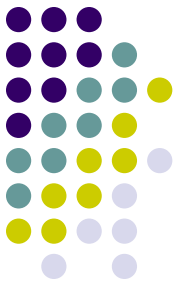
Sensor material properties



	Sapphire	Diamond	GaAs	Si
• Density, g/cm^3	3.98	3.52	5.32	2.33
• Dielectric constant	9.3 - 11.5	5.7	10.9	11.7
• Breakdown field, V/cm	$\sim 10^6$ *	10^7	$4 \cdot 10^5$	$3 \cdot 10^5$
• Resistivity, $\Omega \cdot cm$	$> 10^{14}$	$> 10^{11}$	10^7	10^5
• Band gap, eV	9.9	5.45	1.42	1.12
• El. mobility, $cm^2/(V \cdot s)$	> 600 **	1800	~ 8500	1360
• Hole mobility, $cm^2/(V \cdot s)$	-	1200	-	460
• MIP eh pairs created, $eh/\mu m$	22	36	150	73

* Typical operation field $\sim 1-2 \cdot 10^4 V cm^{-1}$

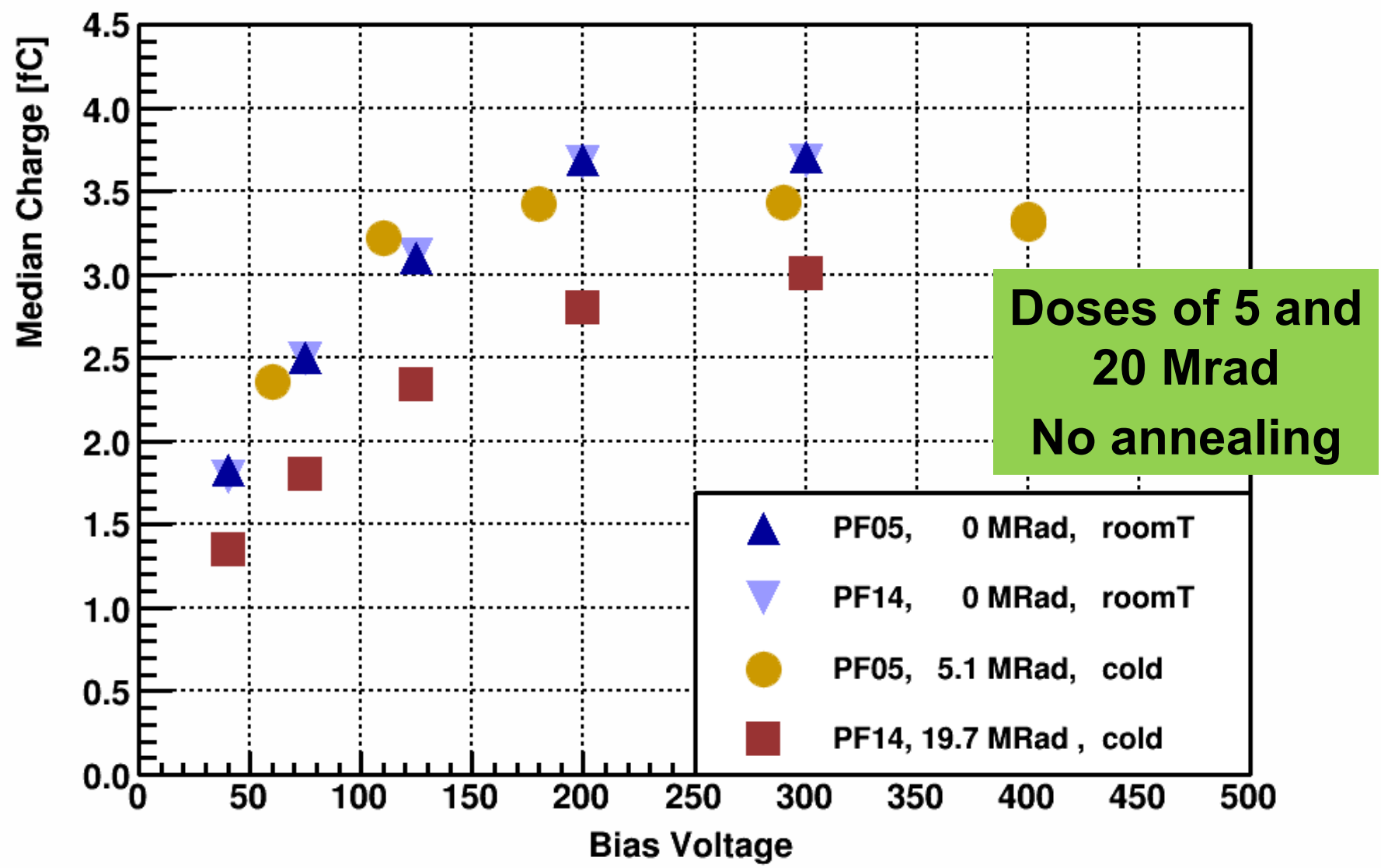
** at $20^\circ C$, ~ 30000 at $40^\circ K$



Radiation Hardness

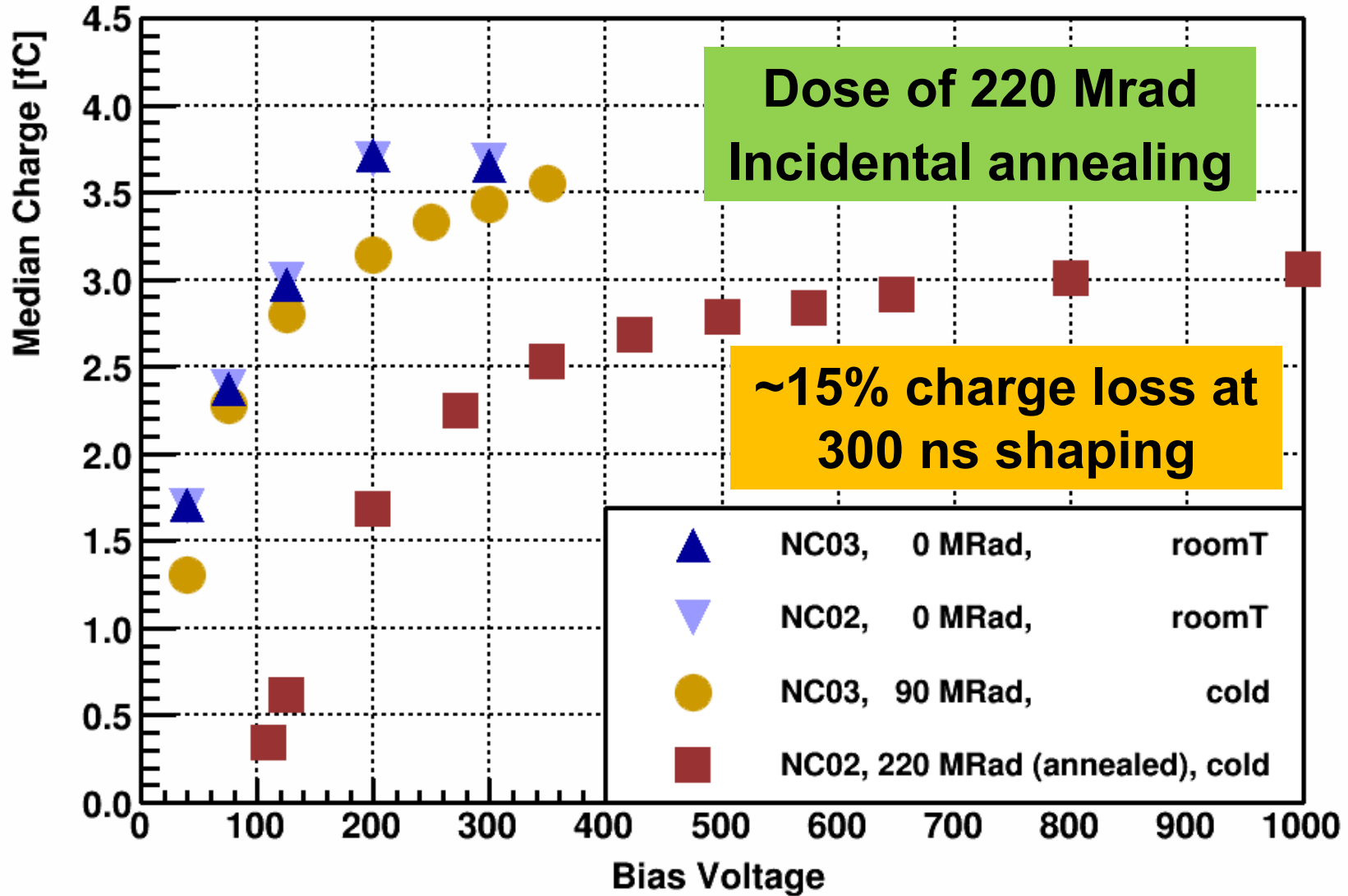
Results: PF sensors

Median Charge vs Bias Voltage, P-type Float Zone sensors

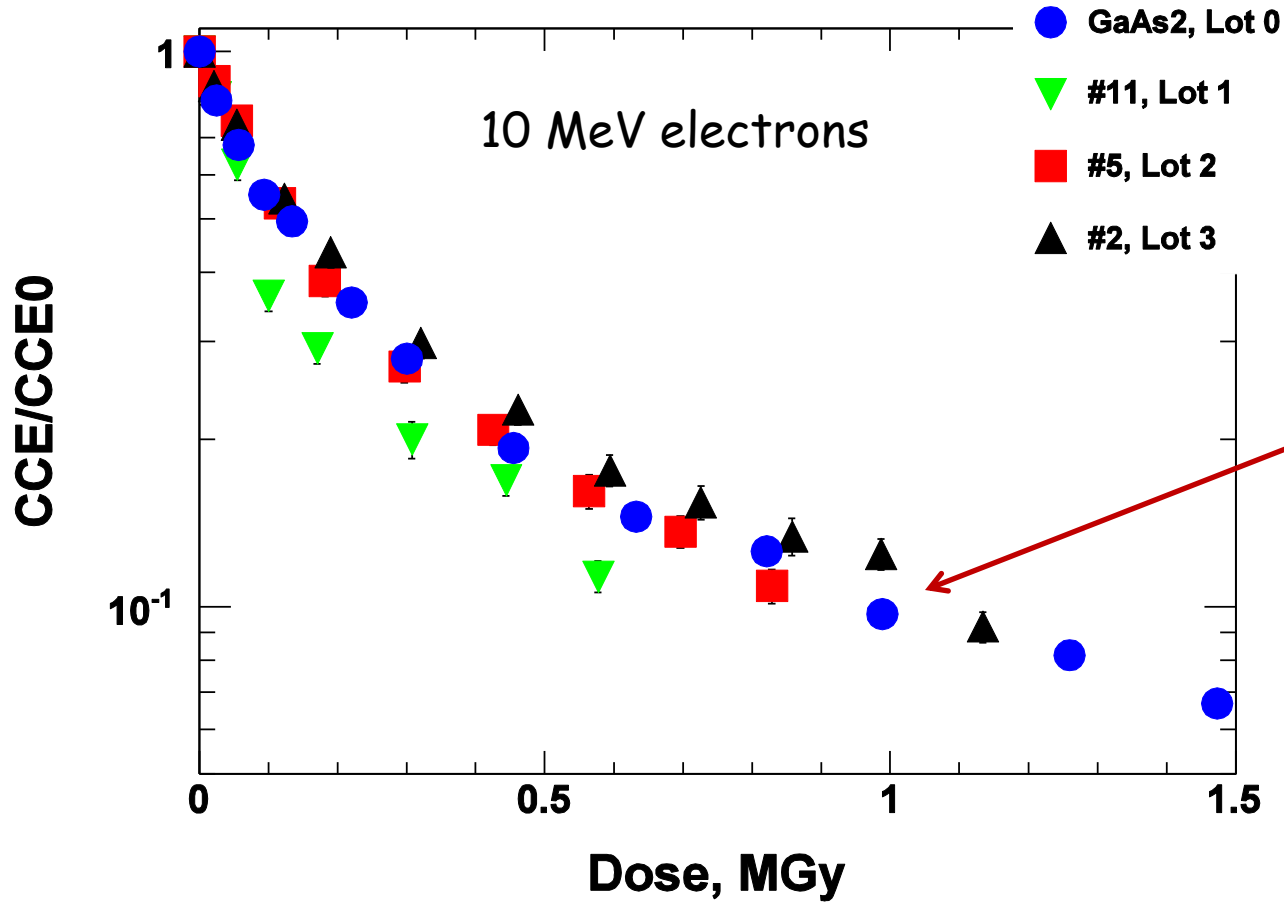
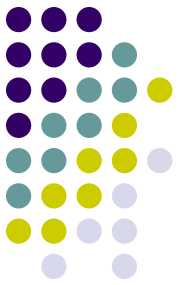


Results: NC sensors

Median Charge vs Bias Voltage, N-type Magnetic Czochalski sensors



Irradiation of GaAs sensors



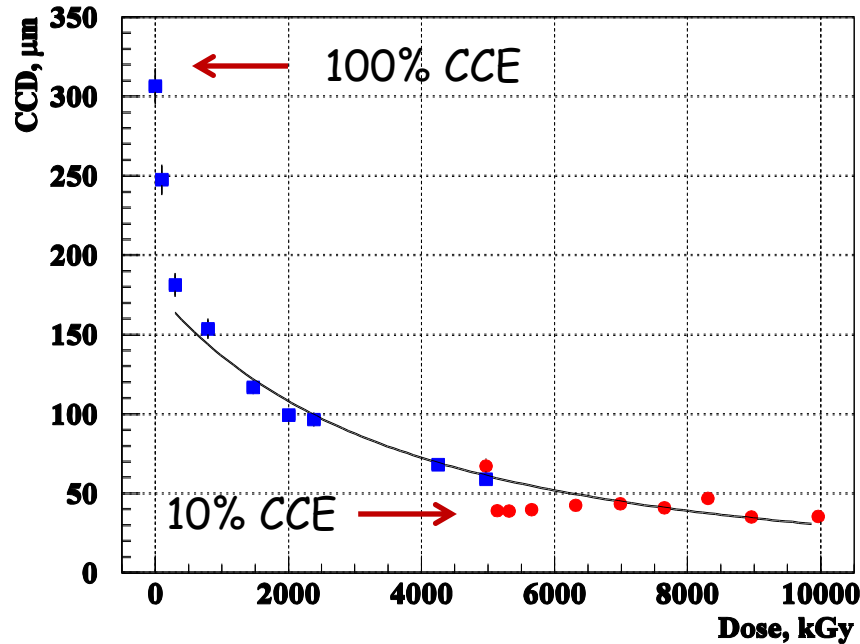
Few μA leakage current after 1 MGy dose (extra noise!)

Irradiation of sapphire and diamond sensors at ~10 MeV electron beam



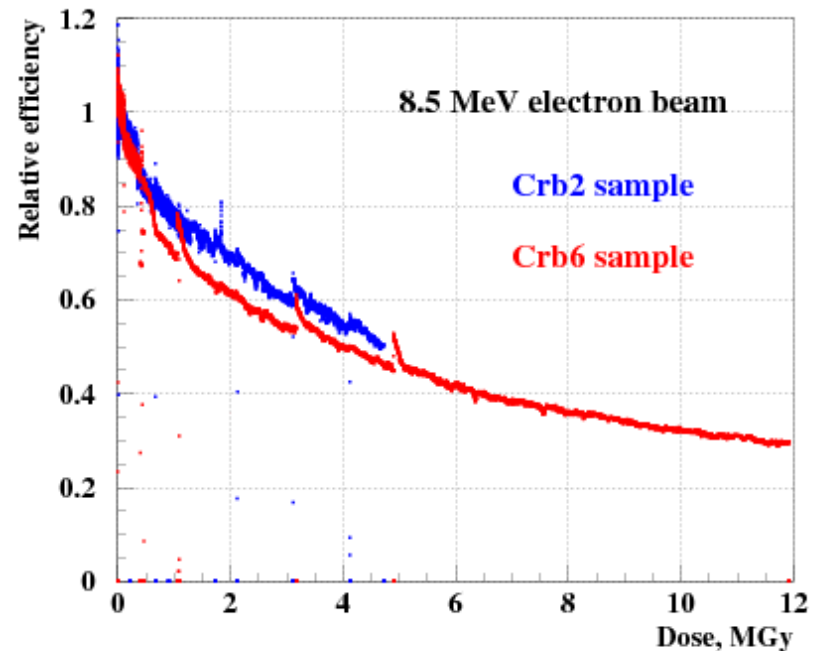
Single crystal CVD diamond

So14_04 scCVD Diamond Irradiation



Single crystal sapphire

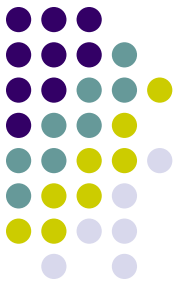
Irradiation of sapphire samples



Leakage current after irradiation is still at few pA level

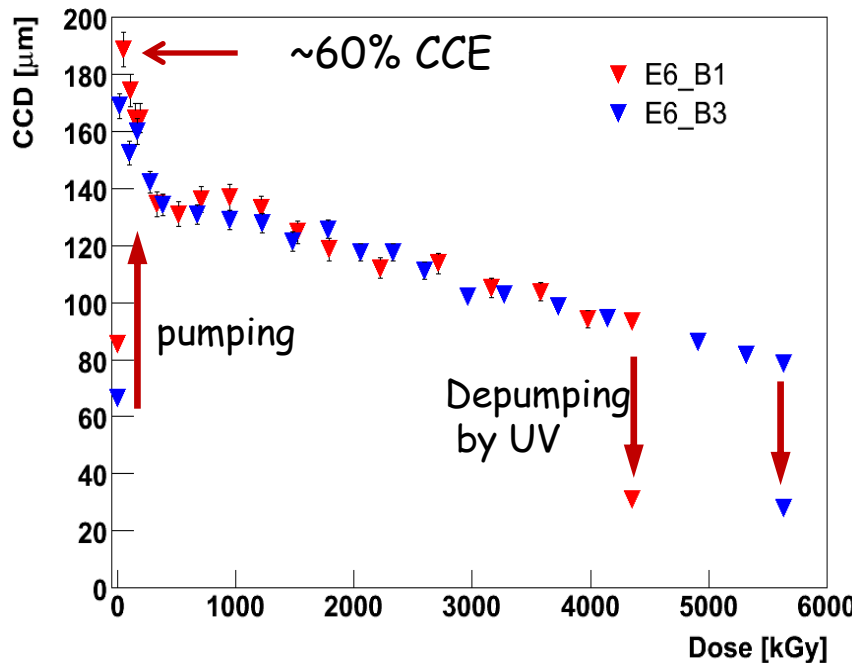
10 MGy $\sim 5 \cdot 10^{16}$ MIPs $\sim 2.5 \cdot 10^{15}$ [1 MeV neq] (NIEL, Summers)

Irradiation of sapphire and diamond sensors at ~10 MeV electron beam



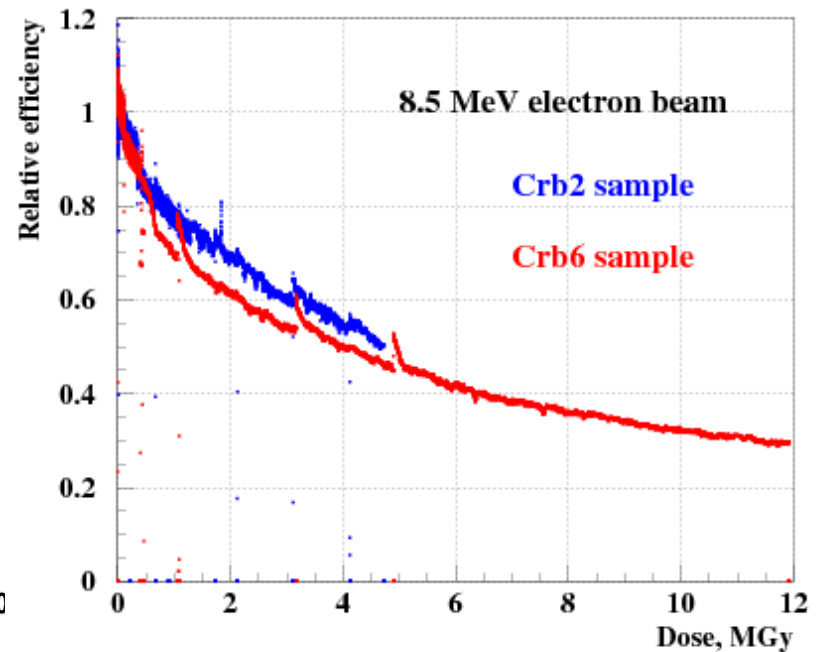
Polycrystalline CVD diamond

E6 samples CCD vs dose at 400V



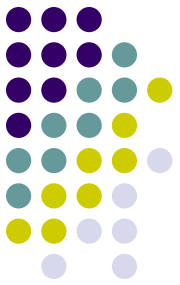
Single crystal sapphire

Irradiation of sapphire samples



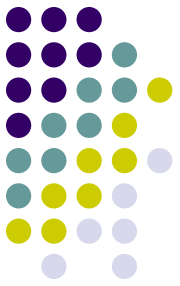
Leakage current after irradiation is still at few pA level

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BeamCal design

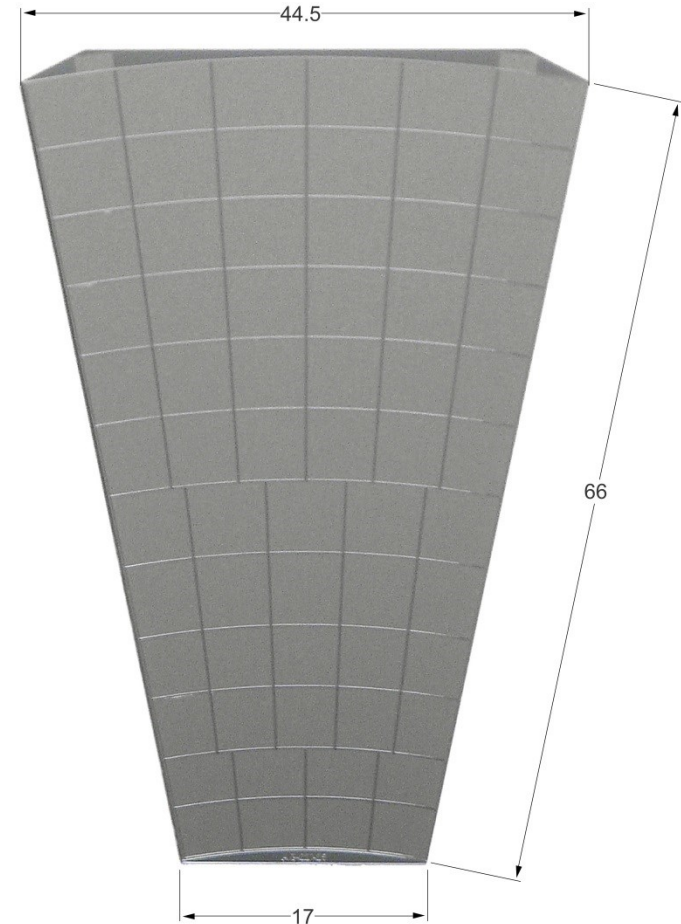
Baseline design



- 30 layers (3.5 mm W + 0.5 mm sensor*)
- $R_{in} = 20$ mm, $R_{out}(sens)=150$ mm
- Sensor material - GaAs

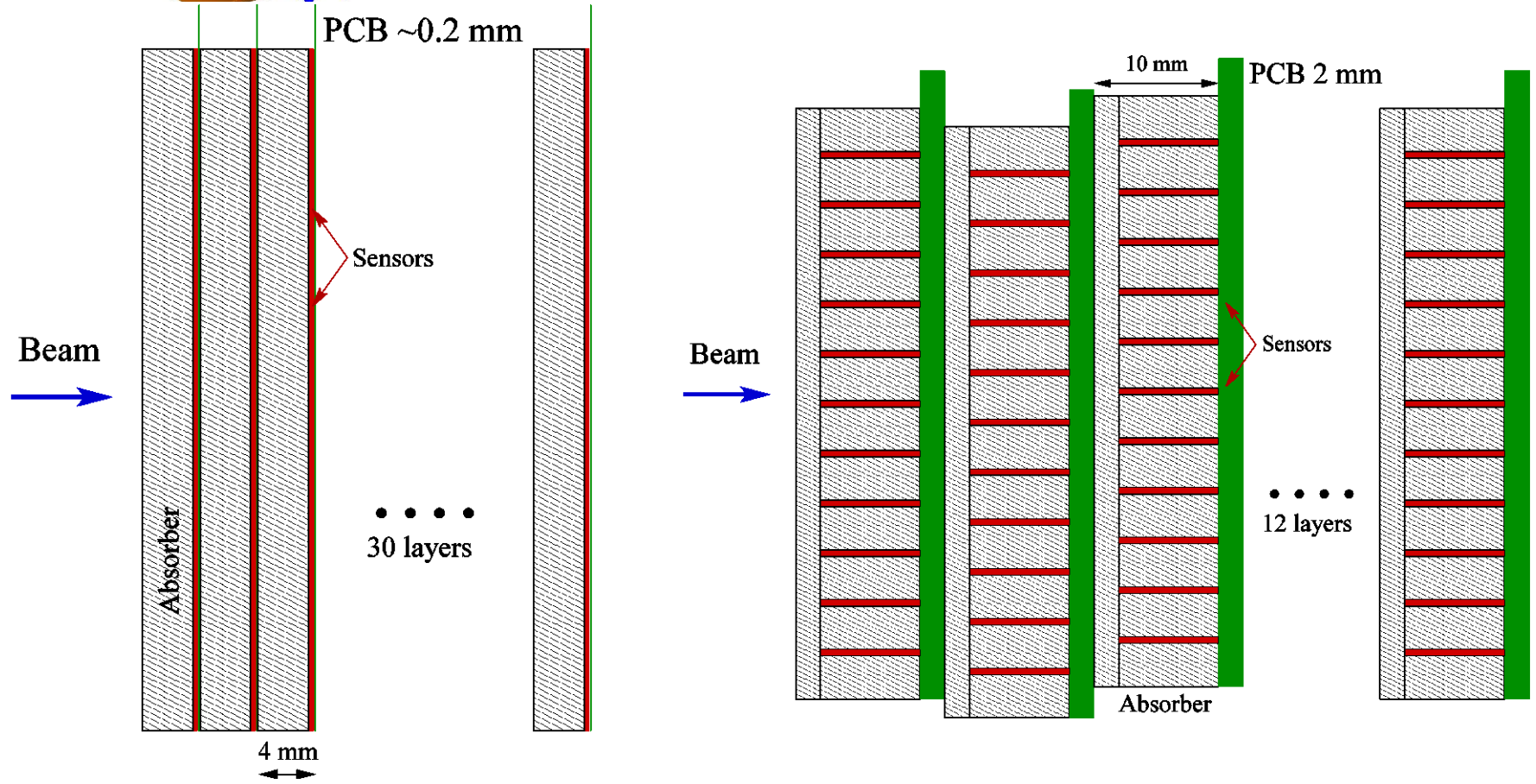
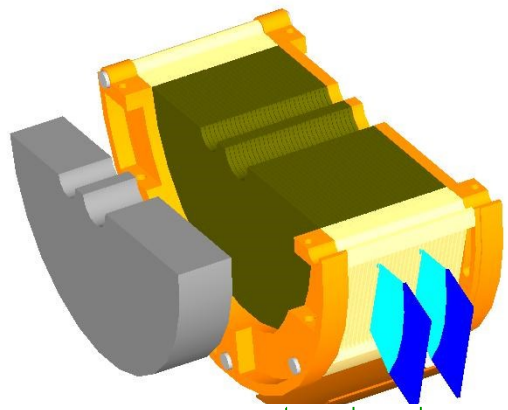
Sensor prototype:

- Wafer size - 74 mm eff. diameter
- Thickness $500\mu\text{m}$ (thinner - problematic)
- 2 rings of sensors (GaAs + Si for outer?)
- Thin fanout PCB (Hans), bonding (2 options)
- Cost ~ 650 Euro/pc (312kE/Calorimeter, even if only inner ring is made out of GaAs)

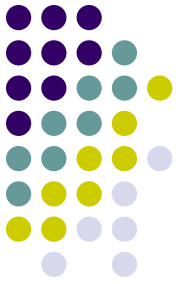




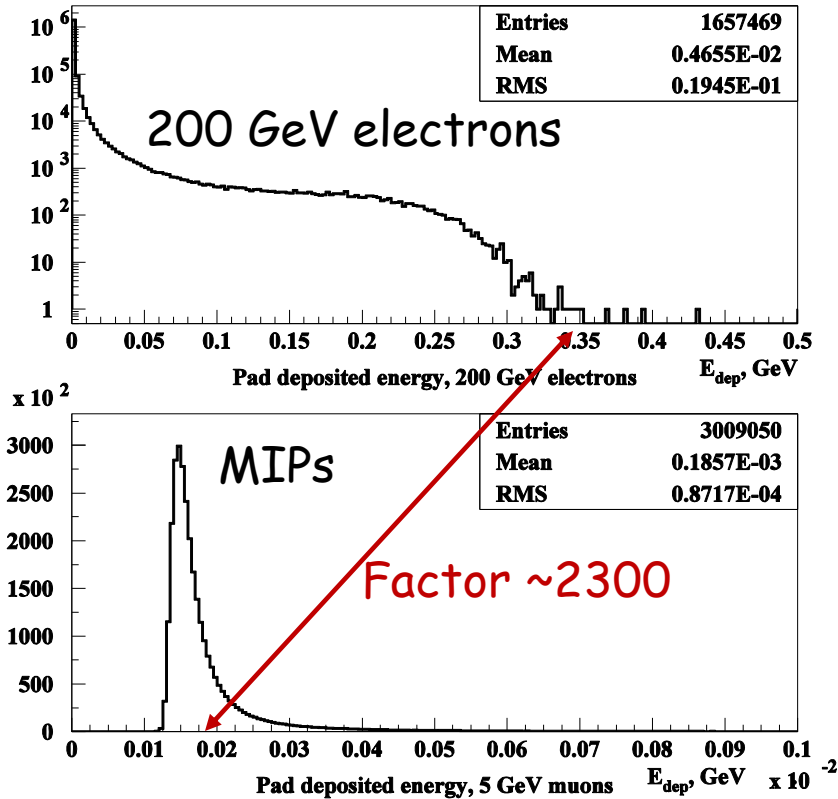
Modification of BeamCal design for sapphire sensors application



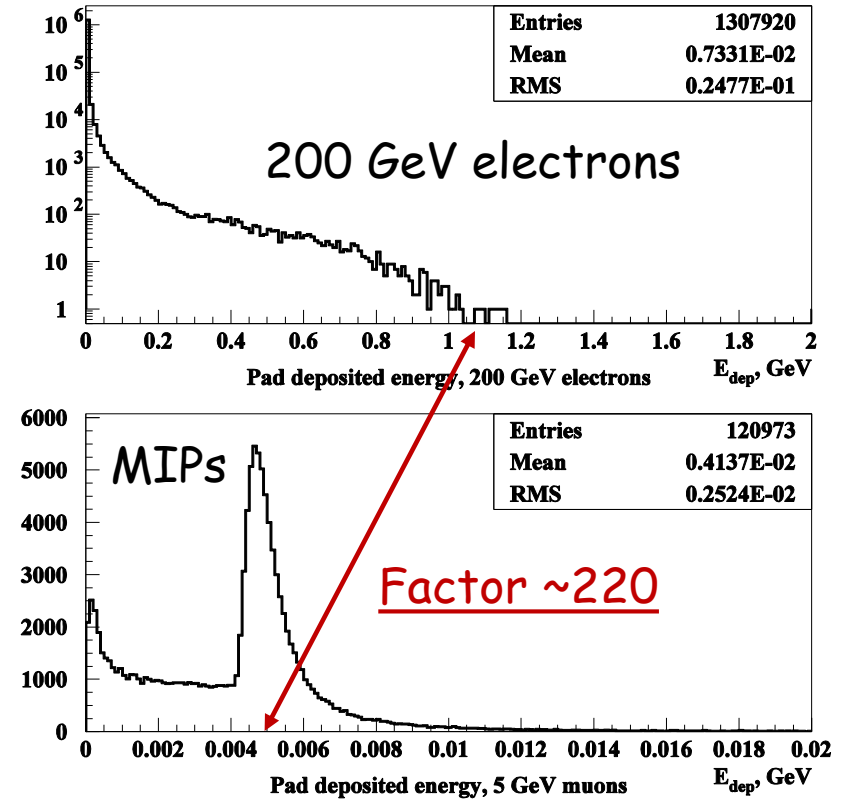
Dynamic range needed for BeamCal Readout (high energy electrons/MIPs)



Baseline design



New sapphire design

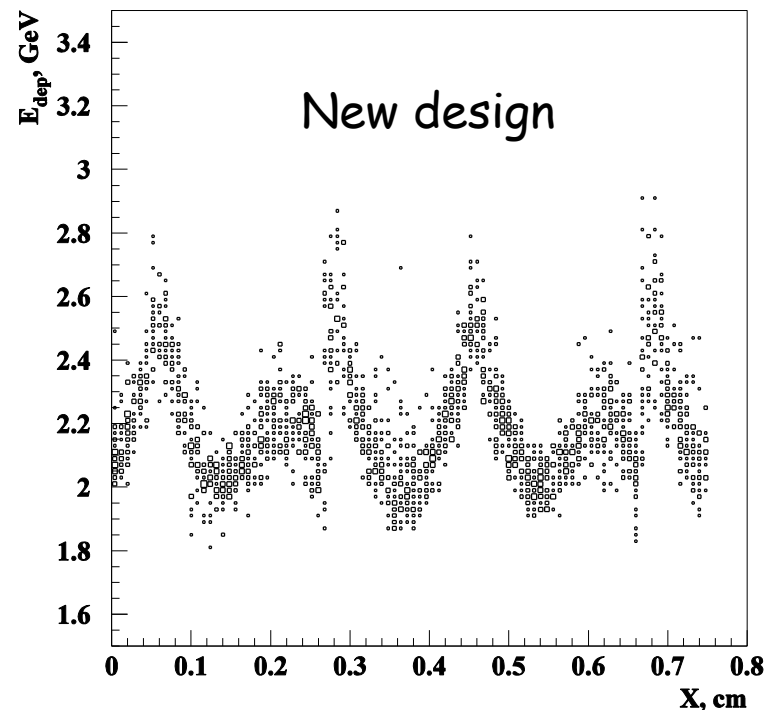
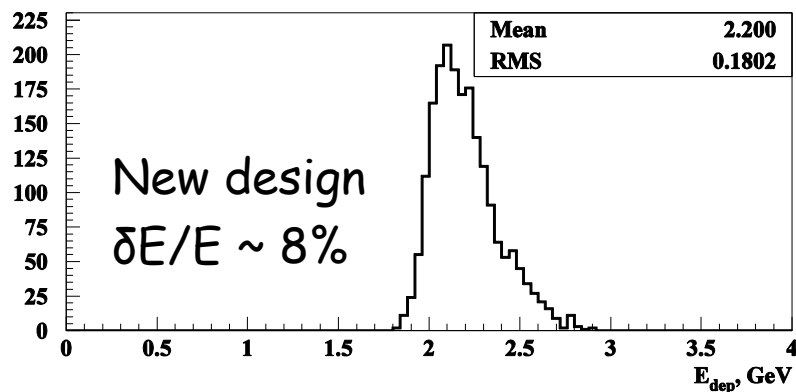
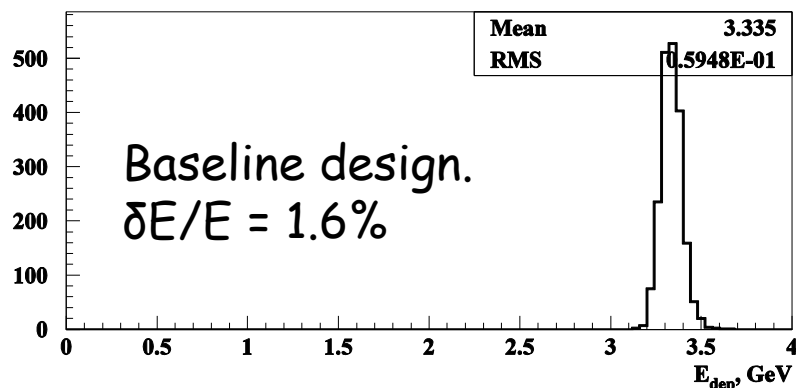


BeamCal energy resolution



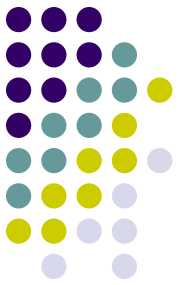
200 GeV electrons,

GEANT3 Monte Carlo



Response nonuniformity in the direction, perpendicular to the strips, depends on relative layer positioning. Further optimization is needed.

Plans



- Prepare 4 GaAs sensor planes for the next test beam
- Sapphire sensors: detailed BeamCal design, MC studies
- Develop sapphire wafers quality control (UV + visible light?)
- New design BeamCal prototype, based on sapphire sensors
- Test beam studies
- Manpower? Resources?